

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/937,463	FUKUDA ET AL.	
Examiner Cong-Lac Huynh		Art Unit 2178	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,966,121	10-1999	Hubbell et al.	715/726
*	B	US-6,032,156	02-2000	Marcus, Dwight	707/104.1
*	C	US-6,154,600	11-2000	Newman et al.	386/4
*	D	US-6,400,832	06-2002	Sevigny, Benoit	382/103
*	E	US-6,452,875	09-2002	Lee et al.	369/30.04
*	F	US-6,544,293	04-2003	Ohanian, Thomas A.	715/500.1
*	G	US-6,597,375	07-2003	Yawitz, Mitchell A.	715/723
*	H	US-6,621,504	09-2003	Nadas et al.	715/723
*	I	US-6,628,303	09-2003	Foreman et al.	715/723
*	J	US-2001/0020953	09-2001	Moriwake et al.	345/723
*	K	US-2004/0078761	04-2004	Ohanian, Thomas A.	715/530
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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